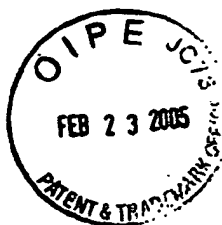


2/05



LIST OF RELATED CASES

<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent Appl. Publication No.</u>	<u>Inventor/ Applicant</u>
245545US2*	10/803,256	03/19/04	2004/0185358 A1	KAMI
263007US0	11/007,784	12/9/04		KONDO, et al.
264314US0	11/030,307	1/7/05		KAMI, et al.
262568US0	11/016,708	12/21/04		KITAJIMA, et al.

*Present Application; listed for information
NFO/get

3/04

SHEET 1 OF 2

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 245545US2		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hidetoshi KAMI			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,871,876	02/16/99	Hiroshi IKUNO, et al.			
	AB	6,030,733	02/29/00	Hidetoshi KAMI, et al.			
	AC	6,326,112	12/04/01	Hiroshi TAMURA, et al.			
	AD	6,641,964	11/04/03	Hiroshi IKUNO, et al.			
	AE	6,573,016	06/03/03	Hidetoshi KAMI, et al.			
	AF	6,653,033	11/25/03	Hidetoshi KAMI, et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AG	11-133825	05/21/99	Japan (with English Abstract)			X
	AH	2002-123067	04/26/02	Japan (with English Abstract)			X
	AI	10-177261	06/30/98	Japan (with English Abstract)			X
	AJ	10-115946	05/06/98	Japan (with English Abstract)			X
	AK	11-184135	07/09/99	Japan (with English Abstract)			X
	AL	10-177263	06/30/98	Japan (with English Abstract)			X
	AM	10-177264	06/30/98	Japan (with English Abstract)			X
	AN	10-177269	06/30/98	Japan (with English Abstract)			X
	AO	2000-147803	05/26/00	Japan (with English Abstract)			X
	AP	2001-235889	08/31/01	Japan (with English Abstract)			X
	AQ	2002-6528	01/09/02	Japan (with English Abstract)			X
	AR	2000-75521	03/14/00	Japan (with English Abstract)			X
	AS	2000-105478	04/11/00	Japan (with English Abstract)			X
	AT	2001-305762	11/02/01	Japan (with English Abstract)			X
	AU	7-92701	04/07/95	Japan (with English Abstract)			X
	AV	8-152721	06/11/96	Japan (with English Abstract)			X
	AW	10-177262	06/30/98	Japan (with English Abstract)			X
	AX	6-313972	11/8/94	Japan (with English Abstract)			X
	AY	10-69104	03/10/98	Japan (with English Abstract)			X
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AZ				<input type="checkbox"/> Additional References sheet(s) attached		
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

3/04

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 245545US2		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hidetoshi KAMI			
				FILING DATE Herewith		GROUP	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AAA	10-186696	07/14/98	Japan (with English Abstract)			X
	AAB	2002-107972	04/10/02	Japan (with English Abstract)			X
	AAC	7-43920	02/14/95	Japan (with English Abstract)			X
	AAD	9-211876	08/15/97	Japan (with English Abstract)			X
	AAE	8-22136	01/23/96	Japan (with English Abstract)			X
	AAF	11-184127	07/09/99	Japan (with English Abstract)			X
	AAG	2000-112162	04/21/00	Japan (with English Abstract)			X
	AAH	2001-51438	02/23/01	Japan (with English Abstract)			X
	AAI	2001-305763	11/02/01	Japan (with English Abstract)			X
	AAJ	2002-107983	04/10/02	Japan (with English Abstract)			X
	AAK	2000-292946	10/20/00	Japan (with English Abstract)			X
	AAL	7-13374	01/17/95	Japan (with English Abstract)			X
	AAM	7-44065	02/14/95	Japan (with English Abstract)			X
	AAN	10-123802	05/15/98	Japan (with English Abstract)			X
	AAO	10-123855	05/15/98	Japan (with English Abstract)			X
	AAP	2000-231246	08/22/00	Japan (with English Abstract)			X
	AAQ	10-123856	05/15/98	Japan (with English Abstract)			X
	AAS	10-246997	09/14/98	Japan (with English Abstract)			X
	AAT	2001-117244	04/27/01	Japan (with English Abstract)			X
	AAU						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AAV						
	AAW						
	AAX						
	AAZ						
Examiner						Date Considered	
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